CLAIMS

1. A contact spring ~~(5, 6)~~ for a testing base ~~(1)~~ for the current testing, in particular high current testing, of an electronic component, which is produced from a spring metal sheet of a predetermined thickness and possesses two, in particular identical, opposing lateral faces, and which has one spring arm ~~(5b, 6b)~~ and one testing arm ~~(5a, 6a)~~ with a testing tip ~~(5f, 6f)~~, wherein the testing arm ~~(5a, 6a)~~ forms an angle with the spring arm ~~(5b, 6b)~~, which enables the testing tip ~~(5f, 6f)~~ to be positioned on a contact surface of the electronic component running approximately parallel to the spring arm ~~(5b, 6b)~~, by means of a relative movement between the testing base ~~(1)~~ and the electronic component,
characterized in that,
the geometry of the lateral faces fulfils the following conditions:

- a dimension L of the distance ~~(5n, 6n)~~ between a point Po and a point Pu is at least 2.3 times a length L1 ~~(5g, 6g)~~
- the point Po is located on the boundary line ~~(5l, 6l)~~ of the lateral face facing towards the electronic component, and comprises a distance from the testing tip ~~(5f, 6f)~~ of 3 to 5 times, in particular 4 times, the length L1
- the point Po forms the apex of an angle in a range between 120° and 150°, in particular of a 135° angle, the one leg ~~(5i, 6i)~~ of which extends in the direction of the relative movement between the testing base ~~(1)~~ and the electronic component towards the electronic component, and the other leg ~~(5k, 6k)~~ of which cuts the boundary line ~~(5m, 6m)~~ of the lateral face facing away from the electronic component at the point Pu
- the length L1 corresponds to the minimum thickness ~~(5g, 6g)~~ of the spring arm ~~(5b, 6b)~~, as viewed in the direction of the relative movement between testing base ~~(1)~~ and electronic component.

2. The contact spring in accordance with Claim 1, characterized in that, on its side facing away from the testing arm ~~(5a, 6a)~~ the spring arm ~~(5b, 6b)~~ of the contact spring ~~(5, 6)~~ has a mounting region ~~(5c, 6c)~~, with which it is anchored in the testing base ~~(1)~~.

3. The contact spring in accordance with Claim 2, characterized in that, the lateral faces of the spring arm ~~(5b, 6b)~~ of the contact spring ~~(5, 6)~~ are widened in the mounting region ~~(5c, 6c)~~ of the contact spring ~~(5, 6)~~.

4. A testing base for the current testing, in particular high current testing, of an electronic component, characterized in that, it has a multiplicity of contact springs ~~(5, 6)~~ in accordance with one of the Claims 1 to 3.

5. The testing base in accordance with Claim 4, characterized in that, a first contact spring ~~(5)~~ and a second contact spring ~~(6)~~ are provided for contact surfaces of the electronic component, which contact springs ~~(5, 6)~~ are arranged such that their lateral faces are in each case located within a plane.

6. The testing base in accordance with Claim 5, characterized in that, the dimension for the distance ~~(5n, 6n)~~ between the points Po and Pu for the first contact spring ~~(5)~~ is at least 2.35 times the length L1, and for the second contact spring ~~(6)~~ is at least 2.75 times the length L1.